

## X-RAY

High Performance X-Ray Fluorescence Measuring Instrument for fast and non-destructive Material Analysis and Coating Thickness Measurement

Neo ALFA FSDD (MCR) / ALFA SDD / ALFA SI-Pin analysis, user-friendly interface Easy to analyze composition and karat results with one push of a button accurate chemistry and karat results within seconds Designed to be compact, taking up minimum desktop space.with Direct Shooting X-Ray, An attractive Design suitable for the showroom floor.Hallmarking Centre And Tunch Lab. Fast certificate results with PC software. Interior lighting and camera allows continuous sample viewing for Best customer security Easy access to the test results

[www.neoXrf.com](http://www.neoXrf.com)





## Key Features

The two most distinctive features of the EXE Series are precision video imaging, and “bottom-up” measurement using a motorized Z-axis with laser-based auto-focus.

An available manual XY stage with 1.5X1.5” travel facilitates easy positioning of small and large parts.

## Configuration

The standard configuration includes a single fixed collimator, solid-state PIN detector Silicon Drift Detector and long-life micro-focus x-ray tube/Silicon Drift Detector

## Specifications

### **X-ray Excitation**

50 W (50kV and 1mA) micro-focused Wanode tube

### **Detector**

AmpTek Silicon Drift Detector (SDD) with 110eV Resolution or Better

### **Focal Depth**

Single fixed focal depth with laser and auto focus

### **Video Magnification**

20x: Standard

### **Working Environment:**

50° F (10°C) to 104°F (40°C) and up to 98% BIL, non-condensing

### **Weight**

25kg

### **Optional Manual XY Sample Stage**

Table Size 11x10”  
Travel 1.5x1.5”

### **Element Range**

Aluminum 13 to Uranium 92

### **Analysis layers and elements**

5 layer (4 layers + base) and 10 elements in each layer  
Composition analysis of up to 25 elements simultaneously

### **Filters/Collimators**

4 primary filters / single collimator (optional dual)

### **Digital Pulse Processing**

4096 CH digital multi-channel analyser with flexible shaping time. Automatic signal processing including dead time correction and escape peak correction.

### **Processor**

Intel, CORE i5 3470 (3.2GHz), 8GB DDB3 Memory, Microsoft Windows 10 Prof, 64bit equivalent

### **Camera optics:**

1/4” CMOS-1280x720 VGA resolution.

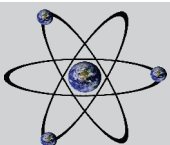
### **Power Supply:**

150W, 100-240 volts, frequency range 47Hz to 63Hz

### **Dimensions (HxWxD)**

Internal 'Comm 14”%, 325mm, 200mm (12”)  
Exterra : 325mm (13”), 350mm (14”), 450mm (18”)

## **Coating Thickness Material Analysis Microhardness Material Testing**



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